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# **Supporting Information**

Fabrication of methylammonium bismuth iodide through interdiffusion of solution-processed BiI<sub>3</sub>/CH<sub>3</sub>NH<sub>3</sub>I stacking layers

Huijia Wang, Jianhua Tian, Kejian Jiang, Yu Zhang, Jinhua Huang, Lian-ming Yang, Bo Guan, Yanlin Song

#### 1. Fabrication of TiO<sub>2</sub> film

Fluorine doped tin oxide (FTO) coated glass substrates (Nippon Sheet Glass Co., Ltd. ~15Ω sq<sup>-1</sup> resistance) were etched with zinc powder and HCl (2 M) and cleaned with soap (Hellmanex) and rinsed with Milli-Q water and ethanol, respectively. Then, the sheets were sonicated for 15 minutes in a solution of acetone: isopropanol (1:1 v/v), rinsed with ethanol and dried with compressed N<sub>2</sub>. After that, a UV/ozone treatment was performed for 15 minutes. Then, a 60 nm thick TiO<sub>2</sub> blocking layer was deposited onto the substrates as follows: spin coating 0.15 M titanium (diisopropoxide) *bis*(2,4-pentanedionate) dissolved in *n*-butanol, and sintering at 125 °C for 5 min, then spin coating the same solution with 0.3 M followed by annealing at 125 °C for 5 min and then heated at 500 °C for 30 min. After cooling down to room temperature, a mesoporous TiO<sub>2</sub> layer was spin coated at 3000 rpm for 30 s using commercial TiO<sub>2</sub> paste diluted in ethanol at weight ratio 2:7, followed by annealing at 125 °C for 5 min and then heated at 500 °C for 30 min. Finally, the cooled film was immersed in 0.02 M aqueous TiCl<sub>4</sub> solution at 70°C for 30 min. After rinsing with DI water and ethanol, the film was heated at 500 °C for 30 min.

### 2. Fabrication of MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> film and device

Two-step spin coating process was employed for the deposition of MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> on the mesoporous TiO<sub>2</sub> film. First, the solution of BiI<sub>3</sub> was prepared by dissolving 472 mg BiI<sub>3</sub> powder (99%, from Energy Chemical) in 1 mL *N*,*N*-Dimethylformamide (DMF, from Sigma-Aldrich). This was mixed ultrasonically for 30 min before being filtered by PTFE syringe filter (0.22 μm). Inside a

nitrogen-filled glovebox, 20μL of the filtered solution was spread over the substrate and spin-cast at 2000 rpm for 5 s, followed by 5000 rpm for 10 s. The BiI<sub>3</sub> film was dried for 30 min before being annealed at 100 °C for 30 min. Subsequently, 100μL MAI solution in isopropanol with various concentrations (3mg/mL, 6mg/mL, 10mg/mL and 20mg/mL) was dropped on the top of BiI<sub>3</sub> film and kept for 30 s, followed by spin-coating at 4000 rpm for 20 s in a glovebox. The film was allowed to anneal at 100 °C for 60 min to form the MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> film.

One-step spin-coating method was used to deposit the MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> film on the TiO<sub>2</sub> mesoporous layers. A MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> solution (0.8M) was prepared by mixing 191mg of MAI, 472mg of BiI<sub>3</sub> in 1 mL DMF. The mixed solution was ultrasonically for 30 min and then filtered through a 0.22 µm PTFE syringe filters. 35µL of MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> solution was dropped onto the substrate and spin-coated at 4000 rpm for 30s. The film was allowed to anneal at 100 °C for 30 min to form the MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> film.

The hole transport layer was prepared by spin-coating a *spiro*-MeOTAD (2,2',7,7'-tetrakis(N,N-di-*p*-methoxyphenylamine)-9,9-spirobifluorene) solution at 4000 rpm for 30 s. The spin-coating formulation was prepared as follows: to 1 mL of chlorobenzene were added 80 mg of *spiro*-MeOTAD, 28.5 μL of 4-*tert*-butylpyridine, and 17.5 μL of a stock solution of 520 mg mL<sup>-1</sup> Li-TFSI in acetonitrile. Finally, An 80 nm thick Au was thermally evaporated as a back contact under a vacuum of 5×10<sup>-5</sup> Torr. The device active area was 4 mm<sup>2</sup>, determined by the overlap of the cathode and anode.

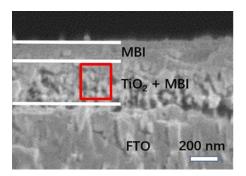
## 3. Film characterization

XRD patterns were recorded by using an X-ray diffractometer (Rigaku, D/MAX RINT-2500) with a CuK radiation source. The surface morphology of the films as well as cross-section was analyzed by using a JEM-7500F field-emission scanning electron microscope (SEM). Absorption spectra of the film samples were recorded by using a Shimadzu UV-vis 1800 spectrophotometer. Steady-state photoluminescence (PL) spectra were acquired using a FLS980 (Edinburgh Instruments, United Kingdom).

#### 4. Device characterization

Current-voltage characteristics were recorded by applying an external potential bias to the cell while recording the generated photocurrent with a Keithley model 2400 digital source meter. The light source was a 300 W collimated xenon lamp (Newport) calibrated with the light intensity to

100 mW cm<sup>-2</sup> under AM 1.5G solar light conditions by a certified silicon solar cell. The *J–V* curve was recorded by the reverse scans with a rate of 200 mV s<sup>-1</sup>. The external quantum efficiency (EQE) for solar cells was performed using a commercial setup (PV-25 DYE, JASCO). A 300 W Xenon lamp was employed as a light source for the generation of a monochromatic beam. Electrochemical impedance spectroscopy (EIS) was carried out by an electrochemical workstation (Zennium, IM6, Germany) over the frequency from 10 mHz to 2 MHz under simulated AM 1.5G (100 mW cm<sup>-2</sup> irradiance).



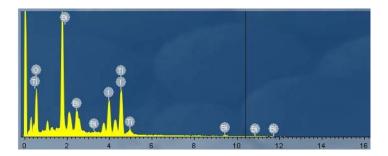
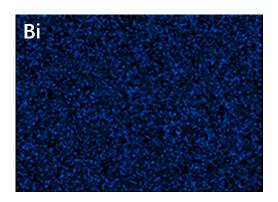


Fig. S1 SEM-EDX elemental analysis of MA<sub>3</sub>Bi<sub>2</sub>I<sub>9</sub> perovskite film.



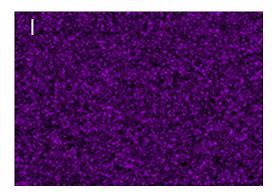


Fig. S2 EDX elemental mapping of Bi and I in MA3Bi2I9 perovskite film.

Table S2 SEM-EDX elemental analysis of MA3Bi2I9 perovskite film

Element	Weight %	Atomic %
I	33.88	9.44
Bi	12.95	2.19

Note: experimental I:Bi ratio: 4.31:1. (For carefully checking the ratio of I:Bi, we do not include atomic% elements such as C, O, N, Ti, Si.)

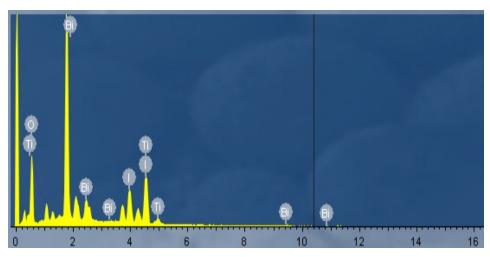
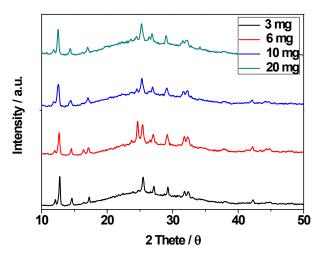


Fig. S3 SEM-EDX elemental analysis of BiI<sub>3</sub> film.

Table S2 SEM-EDX elemental analysis of BiI<sub>3</sub> film

Element	Weight %	Atomic %
I	17.72	3.30
Bi	11.09	2.25

Note: experimental I:Bi ratio: 2.64:1 (For carefully checking the ratio of I:Bi, we do not include atomic% elements such as C, O, N, Ti, Si.).



**Fig. S4** XRD patterns of MBI films deposited by the two-step method with different concentrations of MAI on TiO2 substrate.

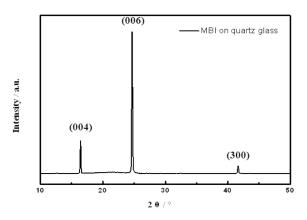
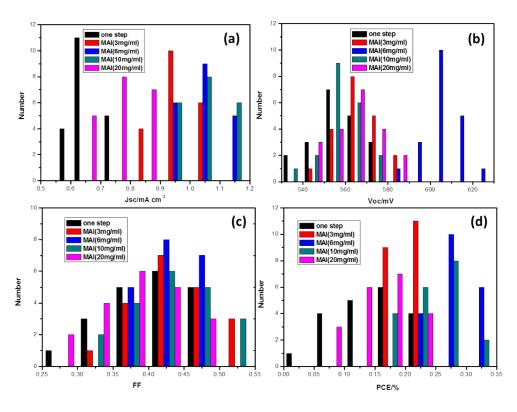
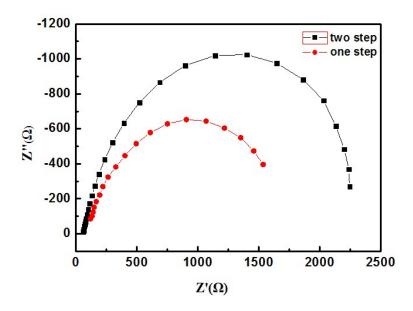


Fig.S5 XRD pattern of MBI on quartz glass substrate.



**Fig.S6** The statistics of photovoltaic performance for devices by one step method and two step method with different concentrations of MBI.



**Fig. S7** Nyquist curves of the devices with MBI film from one-step method and two-step method (MAI, 6 mg/ml) over the frequency range of 10 mHz to 2 MHz under simulated AM 1.5G (100 mW cm<sup>2</sup> irradiance).

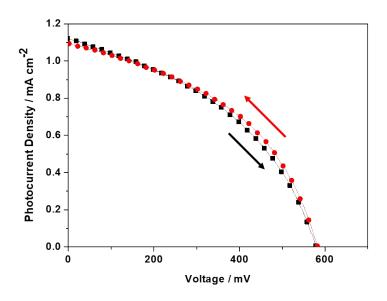
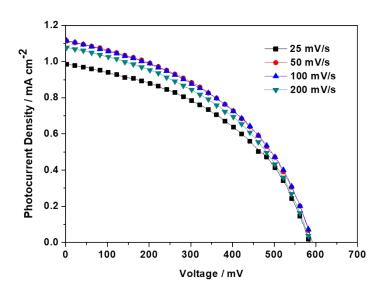


Fig. S8 *I-V* curves with forward and reverse scanning at a rate of 100 mV/s.



**Fig.S9** *I-V* curves with reverse scanning at various rates of 25 to 200 mV/s.